IGBT for Automotive Application 650 V, 30 A

AFGHL30T65RQDN

Using novel field stop IGBT technology, ON Semiconductor's new series of FS4 IGBTs offer the optimum performance for automotive applications. This technology is Short circuit rated and offers high figure of merit with low conduction and switching losses.

Features

- Maximum Junction Temperature: $T_I = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage: $V_{CE(Sat)} = 1.57 \text{ V (Typ.)} @ I_C = 30 \text{ A}$
- 100% of the Parts Tested for I_{LM} (Note 2)
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution
- This Device is Pb-Free and RoHS Compliant

Typical Applications

• E-compressor for HEV/EV, PTC heater for HEV/EV

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-to-Emitter Voltage	V _{CES}	650	V
Gate-to-Emitter Voltage Transient Gate-to-Emitter Voltage	V _{GES}	±20 ±30	V
Collector Current (Note 1) @ T _C = 25°C @ T _C = 100°C	IC	42 30	A
Pulsed Collector Current (Note 2)	I _{LM}	120	Α
Pulsed Collector Current (Note 3)	I _{CM}	120	Α
Diode Forward Current (Note 1) @ T _C = 25°C @ T _C = 100°C	I _F	42 30	Α
Pulsed Diode Maximum Forward Current	I _{FM}	120	Α
$\label{eq:non-expectative} \begin{split} &\text{Non-Repetitive Forward Surge Current} \\ &\text{(Half-Sine Pulse, tp = 8.3 ms, T_C = 25°C)} \\ &\text{(Half-Sine Pulse, tp = 8.3 ms, T_C = 150°C)} \end{split}$	I _{FM}	140 100	Α
Short Circuit Withstand Time V _{GE} = 15 V, V _{CC} = 400 V, T _C = 150°C	t _{SC}	5	μs
Maximum Power Dissipation @ $T_C = 25^{\circ}C$ @ $T_C = 100^{\circ}C$	P _D	230.8 115.4	W
Operating Junction/Storage Temperature Range	T _J , T _{STG}	–55 to +175	°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	TL	265	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

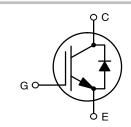
- 1. Value limited by bond wire.
- 2. V_{CC} = 600 V, V_{GE} = 15 V, I_{C} = 90 A, R_{G} = 75 Ω , Inductive Load, 100% Tested.
- 3. Repetitive Rating: pulse width limited by max. Junction temperature.



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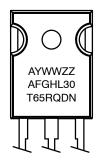
30 A, 650 V, V_{CE(Sat)} = 1.57 V (Typ.)





TO-247-3L CASE 340CX

MARKING DIAGRAM



A = Assembly Site

WW = Work Week Number

Y = Year of Production,

Last Number

ZZ = Assembly Lot Number AFGHL30T65RQDN = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
AFGHL30T65RQDN	TO-247-3L (Pb-Free)	30 Units / Rail

THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal Resistance Junction to Case, for IGBT	$R_{ hetaJC}$	0.65	°C/W
Thermal Resistance Junction to Case, Max for Diode	$R_{ hetaJC}$	1.19	°C/W
Thermal Resistance Junction to Ambient, Max	$R_{ heta JA}$	40	°C/W

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Collector-emitter Breakdown Voltage, Gate-emitter Short-circuited	V _{GE} = 0 V, I _C = 1 mA	BV _{CES}	650	_	-	V
Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0 \text{ V, } I_C = 1 \text{ mA}$	ΔBV _{CES} ΔΤ _J	-	0.53	-	V/°C
Collector-emitter Cut-off Current, Gate-emitter Short-circuited	V _{GE} = 0 V, V _{CE} = V _{CES}	I _{CES}	-	-	30	μΑ
Gate Leakage Current, Collector-emitter Short-circuited	V _{GE} = V _{GES} , V _{CE} = 0 V	I _{GES}	_	_	±400	nA
ON CHARACTERISTICS						
Gate-emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 30 \text{ mA}$	$V_{GE(th)}$	2.90	4.68	5.90	V
Collector-emitter Saturation Voltage	V _{GE} = 15 V, I _C = 30 A V _{GE} = 15 V, I _C = 30 A, T _J = 175°C	V _{CE(sat)}	- -	1.57 1.88	1.75 -	V
DYNAMIC CHARACTERISTICS						
Input Capacitance	V _{CE} = 30 V, V _{GE} = 0 V, f = 1 MHz	C _{ies}	-	1570	_	pF
Output Capacitance		C _{oes}	-	56.20	_	1
Reverse Transfer Capacitance		C _{res}	-	7.12	_	1
Gate Resistance	f = 1 MHz	R_g	-	15	_	Ω
SWITCHING CHARACTERISTICS, IND	OUCTIVE LOAD					
Turn-on Delay Time	$T_J = 25^{\circ}C, V_{CC} = 400 \text{ V},$	t _{d(on)}	-	17.60	-	ns
Rise Time	I_C = 15 A, R_g = 2.5 Ω , V_{GE} = 15 V, Inductive Load	t _r	-	12.80	-	1
Turn-off Delay Time		t _{d(off)}	-	68	-	1
Fall Time		t _f	-	104	-	1
Turn-on Switching Loss		E _{on}	-	0.34	-	mJ
Turn-off Switching Loss		E _{off}	-	0.32	-	
Total Switching Loss		E _{ts}	-	0.65	-	
Turn-on Delay Time	$T_J = 25^{\circ}C$, $V_{CC} = 400 \text{ V}$,	t _{d(on)}	-	19.20	-	ns
Rise Time	I_C = 30 A, R_g = 2.5 Ω , V_{GE} = 15 V, Inductive Load	t _r	-	28.8	-	1
Turn-off Delay Time	1	t _{d(off)}	-	60.80	-	1
Fall Time	1	t _f	-	78.40	-	1
Turn-on Switching Loss		E _{on}	-	0.79	-	mJ
Turn-off Switching Loss		E _{off}	-	0.54	-	1
Total Switching Loss	1	E _{ts}	-	1.30	-	1

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted) (Continued)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS, IN	NDUCTIVE LOAD		•	•		•
Turn-on Delay Time	$T_J = 175^{\circ}C$, $V_{CC} = 400 \text{ V}$,	t _{d(on)}	-	17.60	-	ns
Rise Time	I_C = 15 A, R_g = 2.5 Ω, V_{GE} = 15 V, Inductive Load	t _r	-	16.80	-	
Turn-off Delay Time		t _{d(off)}	-	83.20	-	
Fall Time		t _f	-	196	-	
Turn-on Switching Loss		E _{on}	-	0.53	-	mJ
Turn-off Switching Loss		E _{off}	-	0.69	-	
Total Switching Loss		E _{ts}	-	1.22	-	
Turn-on Delay Time	$T_J = 175^{\circ}C$, $V_{CC} = 400 \text{ V}$,	t _{d(on)}	-	20.80	-	ns
Rise Time	I_C = 30 A, R_g = 2.5 Ω , V_{GE} = 15 V, Inductive Load	t _r	-	36.80	-	1
Turn-off Delay Time		t _{d(off)}	-	72	-	
Fall Time		t _f	-	164	-	
Turn-on Switching Loss		E _{on}	-	1.14	-	mJ
Turn-off Switching Loss		E _{off}	-	1.09	-	
Total Switching Loss		E _{ts}	-	2.23	-	
Gate Charge Total	$V_{CE} = 400 \text{ V}, I_{C} = 30 \text{ A}, V_{GE} = 15 \text{ V}$	Qg	-	37.22	-	nC
Gate-to-Emitter Charge		Q _{ge}	-	11.34	-	
Gate-to-Collector Charge		Q _{gc}	-	10.26	-	
DIODE CHARACTERISTIC						
Diode Forward Voltage	I _F = 30 A, T _J = 25°C	V_{FM}	-	1.7	2.0	V
	I _F = 30 A, T _J = 175°C		-	1.74	-	
Reverse Recovery Energy	$I_F = 30 \text{ A}, \text{ d}I_F/\text{d}t = 1000 \text{ A}/\mu\text{s}, \\ T_J = 175^{\circ}\text{C}$	E _{rec}	-	205.43	-	μJ
Diode Reverse Recovery Time	I _F = 30 A, dI _F /dt = 1000 A/μs	T _{rr}	-	39	-	ns
	$I_F = 30 \text{ A}, \text{ d}I_F/\text{d}t = 1000 \text{ A}/\mu\text{s}, \\ T_J = 175^{\circ}\text{C}$		_	85.43	-	
Diode Reverse Recovery Charge	I _F = 30 A, dI _F /dt = 1000 A/μs	Q _{rr}	-	344.99	-	nC
	$I_F = 30 \text{ A}, dI_F/dt = 1000 \text{ A}/\mu\text{s},$ $T_J = 175^{\circ}\text{C}$		-	1002	-	1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

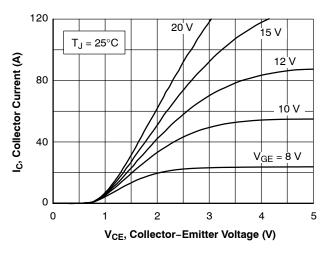


Figure 1. Typical Output Characteristics

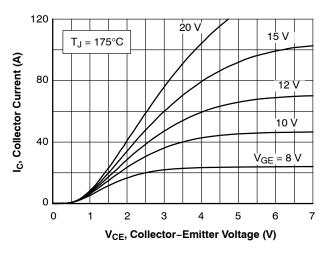


Figure 2. Typical Output Characteristics

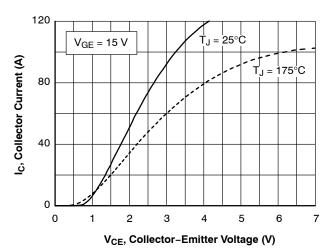


Figure 3. Typical Saturation Voltage Characteristics

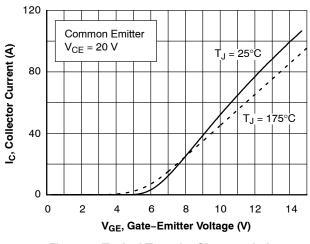


Figure 4. Typical Transfer Characteristics

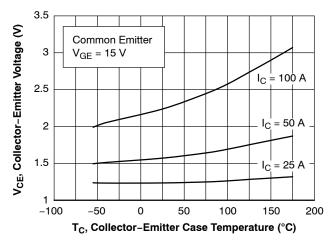


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

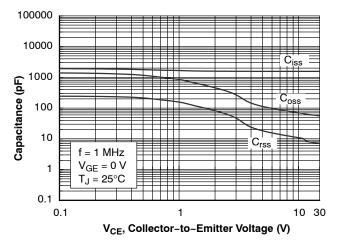


Figure 6. Capacitance Characteristics

TYPICAL CHARACTERISTICS (Continued)

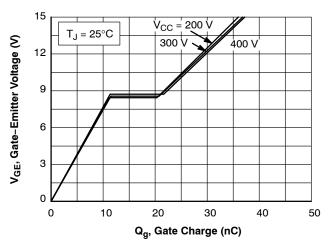


Figure 7. Gate Charge Characteristics

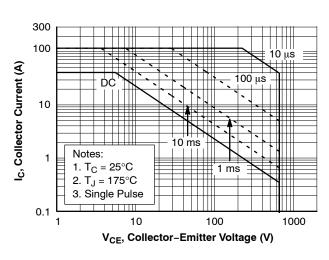


Figure 8. SOA Characteristics

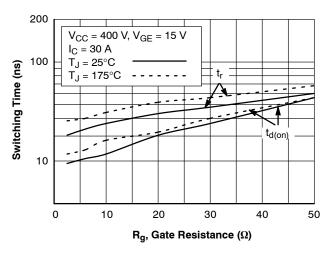


Figure 9. Turn-on Characteristics vs.
Gate Resistance

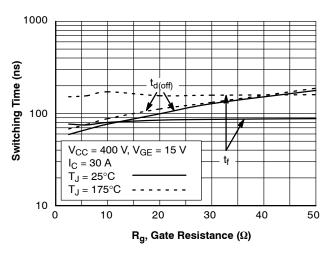


Figure 10. Turn-off Characteristics vs.
Gate Resistance

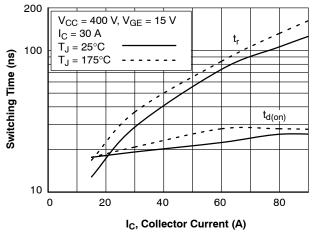


Figure 11. Turn-on Characteristics vs.
Collector Current

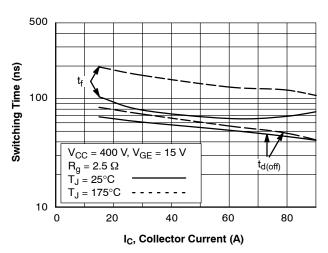


Figure 12. Turn-off Characteristics vs.
Collector Current

TYPICAL CHARACTERISTICS (Continued)

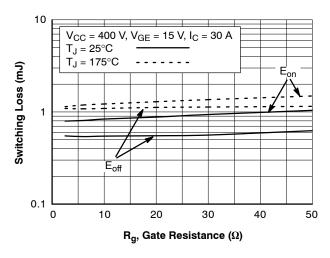


Figure 13. Switching Loss vs. Gate Resistance

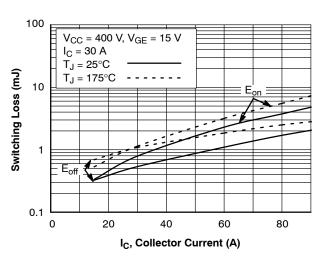


Figure 14. Switching Loss vs. Collector Current

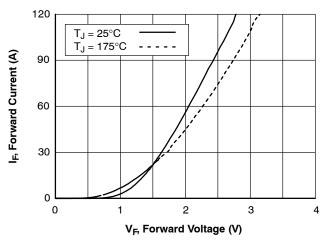


Figure 15. Forward Characteristics

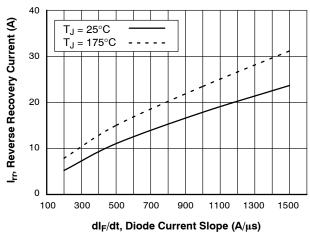


Figure 16. Reverse Recovery Current

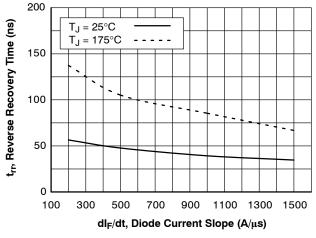


Figure 17. Reverse Recovery Time

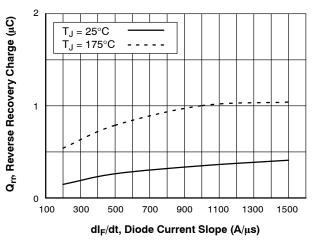


Figure 18. Stored Charge

TYPICAL CHARACTERISTICS (Continued)

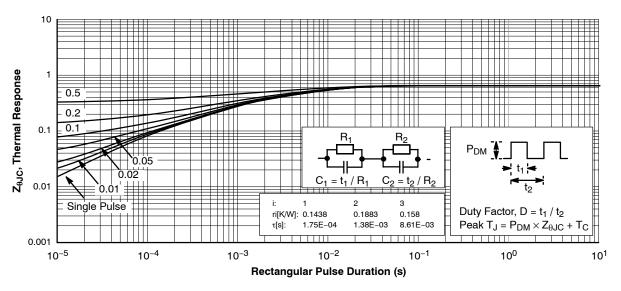


Figure 19. Transient Thermal Impedance of IGBT

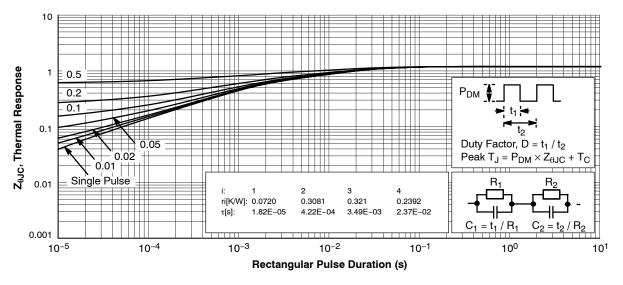
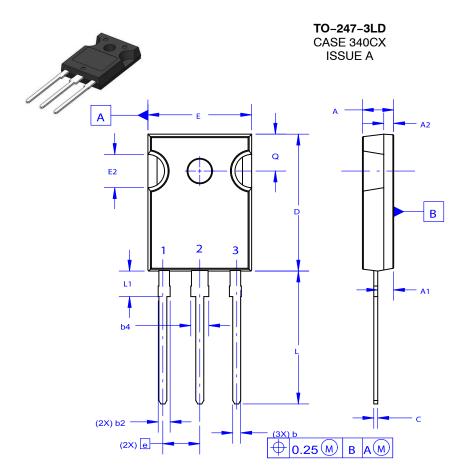
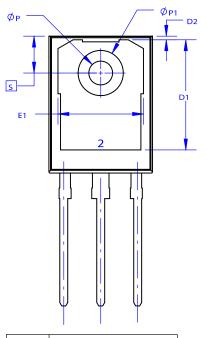


Figure 20. Transient Thermal Impedance of Diode



DATE 06 JUL 2020



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

 B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " =", may or may not be present. Some products may not follow the Generic Marking.

DIM	MIL	LIMETER	S
DIM	MIN	NOM	MAX
Α	4.58	4.70	4.82
A 1	2.20	2.40	2.60
A2	1.40	1.50	1.60
D	20.32	20.57	20.82
Е	15.37	15.62	15.87
E2	4.96	5.08	5.20
е	~	5.56	~
L	19.75	20.00	20.25
L1	3.69	3.81	3.93
ØΡ	3.51	3.58	3.65
Q	5.34	5.46	5.58
S	5.34	5.46	5.58
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
С	0.51	0.61	0.71
D1	13.08	~	~
D2	0.51	0.93	1.35
E1	12.81	~	~
ØP1	6.60	6.80	7.00

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